Current trends in atomic force microscopy techniques

Dr. Li Ang

ABSTRACT
Atomic force microscopy (AFM) has been known as an ultra-sensitive and versatile surface analytical tool for the past 25 years since its invention. Apart from its traditional applications in scanning surface topography of many kinds of materials, it has been developed for characterizing surface mechanical, electrical and magnetical properties with outstanding spatial and temporal resolutions. Over years of innovation, the instrumental barrier of operation has also been lowered dramatically to enable less experienced users to obtain expert level results in an easy and automated manner. In this talk, the most recent developments and applications of AFM techniques in the areas of easy scan, quantitative mechanical mapping and fast speed scanning will be introduced.

BIOGRAPHY
Dr. Li Ang obtained his PhD degree from National University of Singapore and finished 3 years postdoctoral training in Singapore-MIT Alliance. He has more than 8 years experiences of using AFM in the area of biomechanics and has published more than 20 journal papers and 3 book chapters and earned many awards including Young Investigator Award (gold) in 6th World Congress of Biomechanics and First Place of Interactional Scanning Probe Microscopy Image Contest 2009. Currently, Dr. Li is serving as an application scientist for Bruker Nano surface Division based in Singapore.

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All are welcome!

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